

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination PAVEY, NICHOLAS	
		Examiner Hugh Jones	Art Unit 2128	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-6,675,138	01-2004	Hollander et al.	703/13
	D	US-6,694,497	02-2004	Pavey, Nicholas	716/4
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Liu et al.; Efficient coverage analysis metric for HDL design validation; IEEE Proc. Comp. & Digital Techniques; pp. 1-6; 1/2001.
	V	Gharehbaghi et al.; Behavioral test generation for VHDL processes; IEEE Proc. 12th Int. Conf. Microelectronics; pp. 123-126; 10/2000.
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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